Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
[barcode]	10/613,316	CHEN, WEI-ZEN
	Examiner	**Art Unit**
	Joseph Chang	2817

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)	

CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
331	45	331	2						
INTERNATIONAL CLASSIFICATION		327	147						
H 0 3 L	7/06								
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Joseph Chang (Assistant Examiner) (Date)	BENNY LEE PRIMARY EXAMINER ART UNIT 2817 *Benny Lee* 18 Feb 2005 (Primary Examiner) (Date)	Total Claims Allowed: 3
[signature] 2/23/05 (Legal Instruments Examiner) (Date)		O.G. Print Claim(s): 1 / O.G. Print Fig.: 2

☐ Claims renumbered in the same order as presented by applicant ☐ CPA ☐ T.D. ☐ R.1.47

Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
	1		31		61		91		121		151		181
1	2		32		62		92		122		152		182
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	7		37		67		97		127		157		187
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	29		59		89		119		149		179		209
	30		60		90		120		150		180		210

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